P20987.A01

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant : Tsuyoshi NAKAJIMA et al.

Serial No : Not Yet Assigned

Filed : Concurrently Herewith

For : METHOD AND SYSTEM FOR DETECTING A DEFECT IN PROJECTED

PORTIONS OF AN OBJECT HAVING THE PROJECTED PORTIONS FORMED IN THE SAME SHAPE WITH A

PREDETERMINED PITCH ALONG AN ARC

PRELIMINARY AMENDMENT

Commissioner of Patents and Trademarks Washington, D.C. 20231

Sir:

Prior to calculation of the filing fees and the examination of the above-identified patent application on the merits, the Examiner is respectfully requested to amend the claims as follows:

IN THE CLAIMS

Please amend the claims as follows (a marked-up copy of the claim amendments is provided as an attachment to this Amendment):

5. (Amended-Clean Text) The system for detecting a defect on an object having projected portions formed in the same shape along an arc with a predetermined pitch,

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according to claim 2, further comprising a lighting box for placing the inspected object thereon, said imaging means being arranged opposite to an illuminating surface of the lighting box.

Please add new claims 7 and 8 as follows:

---7. The system for detecting a defect on an object having projected portions formed in the same shape along an arc with a predetermined pitch, according to claim 4, further comprising a lighting box for placing the inspected object thereon, said imaging means being arranged opposite to an illuminating surface of the lighting box.

8. The system for detecting a defect on an object having projected portions formed in the same shape along an arc with a predetermined pitch, according to claim 7, wherein said imaging means is provided with a band pass filter for eliminating, as deleterious light, light having wavelengths other than those of light for said lighting box to illuminate the object with.---

REMARKS

By the above amendment, claim 5 has been amended and claims 7 and 8 have been added to delete multiple dependency.

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If there should be any questions, the Examiner is invited to contact the undersigned at the telephone number listed below.

Respectfully submitted, Tsuyoshi NAKAJIMA et al.

Bruce H. Bernstein

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MARKED-UP COPY OF AMENDED CLAIMS

5. (Amended) The system for detecting a defect on an object having projected portions formed in the same shape along an arc with a predetermined pitch, according to claim 2 [or 4], further comprising a lighting box for placing the inspected object thereon, said imaging means being arranged opposite to an illuminating surface of the lighting box.